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## STS3DPF60L

# DUAL P-CHANNEL 60V - 0.10 Ω - 3A SO-8 STripFET™ MOSFET

**Table 1: General Features** 

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
STS3DPF60L	60 V	< 0.12 Ω	3 A

- TYPICAL R<sub>DS</sub>(on) = 0.10 Ω @ 10V
- STANDARD OUTLINE FOR EASY AUTOMATED SURFACE MOUNT ASSEMBLYY
- LOW THRESHOLD DRIVE

### **DESCRIPTION**

This MOSFET is the latest development of STMicroelectronis unique "Single Feature Size™" stripbased process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

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### **APPLICATIONS**

■ DC-DC CONVERTERS



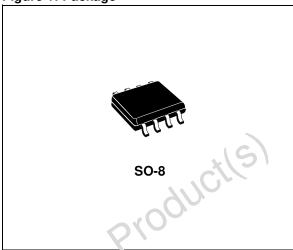


Figure 2: Internal Schematic Diagram

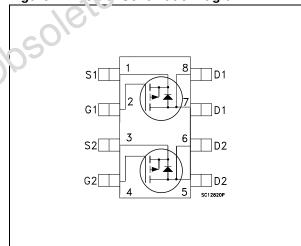


Table 2. Order Codes

PART NUMBER		MARKING	PACKAGE	PACKAGING
STS3D	PF60L	S3DPF60L	SO-8	TAPE & REEL

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**Table 3: Absolute Maximum ratings** 

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	60	V
V <sub>DGR</sub>	Drain-gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	60	V
V <sub>GS</sub>	Gate- source Voltage	± 16	V
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 25°C Drain Current (continuous) at T <sub>C</sub> = 100°C	3 1.9	A A
I <sub>DM</sub> (•)	Drain Current (pulsed)	12	Α
P <sub>tot</sub>	Total Dissipation at T <sub>C</sub> = 25°C	2	W
T <sub>stg</sub>	Storage Temperature	-55 to 150	°C
Tj	Operating Junction Temperature	-95 to 190	

<sup>(•)</sup> Pulse width limited by safe operating area.

### **Table 4: Thermal Data**

Rthj-amb	(*)Thermal Resistance Junction-ambient	62.5	°C/W
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<sup>(\*)</sup> When Mounted on 1 inch<sup>2</sup> FR-4 board, 2 oz of Cu t  $\leq$  10 s

### **ELECTRICAL CHARACTERISTICS** (T<sub>CASE</sub> =25°C UNLESS OTHERWISE SPECIFIED)

### Table 5: On/Off

V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	$I_D$ = 250 μA, $V_{GS}$ = 0 $V_{DS}$ = Max Rating $V_{DS}$ = Max Rating , $T_{C}$ = 125°C	60		1	V µA
I <sub>DSS</sub>			3		1	пΑ
	,	VDS = IVIAX HAIITY, IC= 125 C			10	μΑ
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 16 V			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1.5			V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1.5 A V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 1.5 A		0.10 0.130	0.12 0.160	Ω Ω
10	Produci					

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### **ELECTRICAL CHARACTERISTICS (CONTINUED)**

**Table 6: Dynamic** 

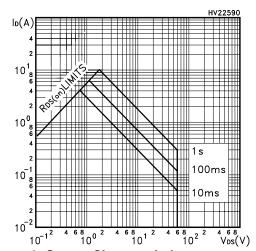
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
gfs (*)	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 3 A		7.2		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V f = 1 MHz V_{GS} = 0$		630 121 49		pF pF pF
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$\begin{aligned} V_{DD} &= 30 \text{ V} \text{ , } I_D = 1.5 \text{ A} \\ R_G &= 4.7  \Omega, \text{ V}_{GS} = 4.5 \text{ V} \\ \text{(see Figure 16)} \end{aligned}$		124 54 39 14.5		ns ns ns ns
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V <sub>DD</sub> = 48V, I <sub>D</sub> = 3A V <sub>GS</sub> =4.5V (see Figure 19)		11.6 4.5 4.7	15.7	nC nC nC

### **Table 7: Source Drain Diode**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Uni
I <sub>SD</sub> I <sub>SDM</sub> (•)	Source-drain Current Source-drain Current (pulsed)			-91/	3 12	A A
V <sub>SD</sub> (*)	Forward On Voltage	I <sub>SD</sub> = 3 A, V <sub>GS</sub> = 0	01	0	1.2	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	I <sub>SD</sub> = 3 A, di/dt = 100A/μs V <sub>DD</sub> = 30 V, T <sub>j</sub> = 150°C (see Figure 17)	3	44 68.2 3.1		ns nC A
		Ob				
	4	5)				
	ie Producile	3)				



Figure 3: Safe Operating Area



**Figure 4: Output Characteristics** 

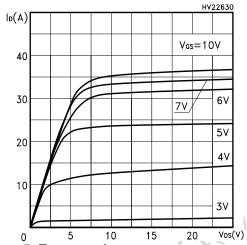


Figure 5: Transconductance

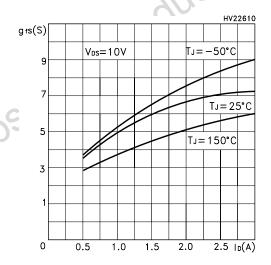
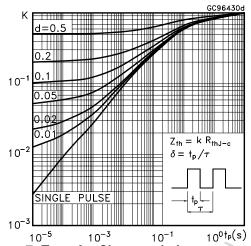


Figure 6: Thermal Impedance



**Figure 7: Transfer Characteristics** 

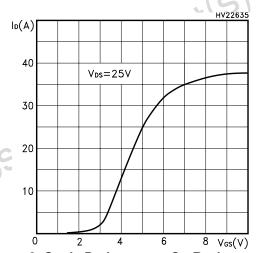
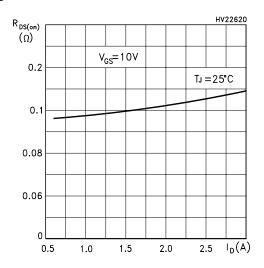


Figure 8: Static Drain-source On Resistance



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Figure 9: Gate Charge vs Gate-source Voltage

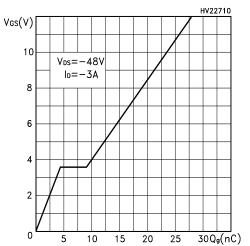


Figure 10: Normalized Gate Thereshold Voltage vs Temperature

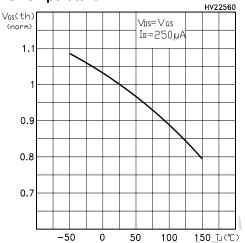


Figure 11: Dource-Drain Diode Forward Characteristics

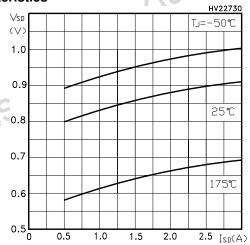


Figure 12: Capacitance Variations

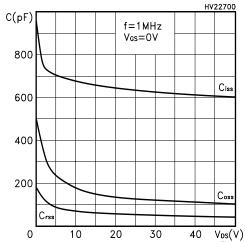


Figure 13: Normalized On Resistance vs Temperature

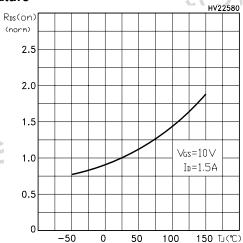


Figure 14: Normalized Breakdown Voltage vs Temperature

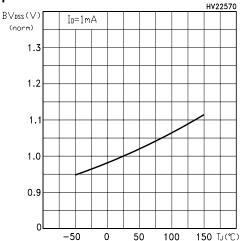
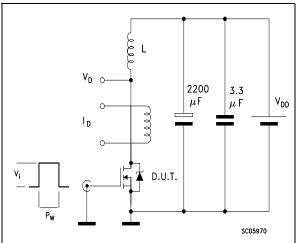
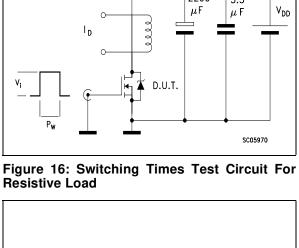


Figure 15: Unclamped Inductive Load Test Circuit





 $R_{L}$ 

 $V_{D}$ 

 $^{3.3}_{\mu}$  F

 $V_{DD}$ 

2200

Figure 17: Test Circuit For Inductive Load Switching and Diode Recovery Times

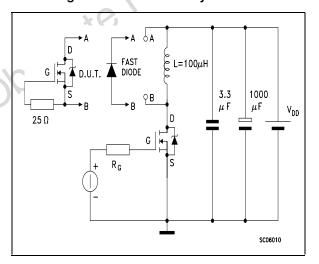


Figure 18: Unclamped Inductive Wafeform

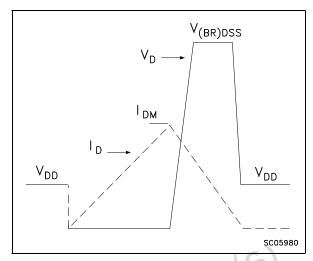
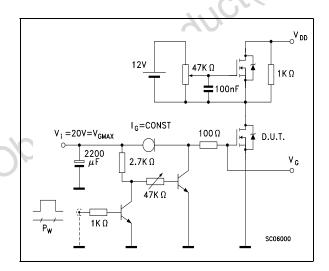
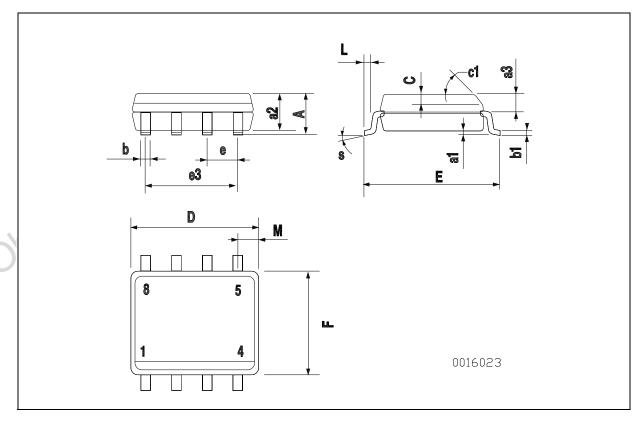


Figure 19: Gate Charge Test Circuit



## **SO-8 MECHANICAL DATA**

DIM.	mm.			inch		
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α			1.75			0.068
a1	0.1		0.25	0.003		0.009
a2			1.65			0.064
аЗ	0.65		0.85	0.025		0.033
b	0.35		0.48	0.013		0.018
b1	0.19		0.25	0.007		0.010
С	0.25		0.5	0.010		0.019
c1			45	(typ.)		
D	4.8		5.0	0.188		0.196
E	5.8		6.2	0.228		0.244
е		1.27			0.050	
e3		3.81			0.150	
F	3.8		4.0	0.14		0.157
L	0.4		1.27	0.015		0.050
M			0.6			0.023
S		•	1) 8	max.)	•	•



**Table 8: Revision History** 

Date	Revision	Description of Changes
16-Sep-2004	1	New release.

Obsolete Product(s).

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